

# Resource Summary Report

Generated by T1D on Aug 24, 2026

## JEOL: JSM-F100 Field Emission Scanning Electron Microscope (SEM)

RRID:SCR\_020187

Type: Tool

### Proper Citation

JEOL: JSM-F100 Field Emission Scanning Electron Microscope (SEM)  
(RRID:SCR\_020187)

### Resource Information

**URL:** <https://www.jeolusa.com/PRODUCTS/Scanning-Electron-Microscopes-SEM/FE-SEM/JSM-F100>

**Proper Citation:** JEOL: JSM-F100 Field Emission Scanning Electron Microscope (SEM)  
(RRID:SCR\_020187)

**Description:** Scanning electron microscope that offers high spatial resolution imaging and analysis at nanoscale

**Resource Type:** instrument resource

**Keywords:** Jeol, JEOL, Scanning Electron Microscope, Instrument Equipment, USEDit,

**Availability:** Commercially available

**Resource Name:** JEOL: JSM-F100 Field Emission Scanning Electron Microscope (SEM)

**Resource ID:** SCR\_020187

**Alternate IDs:** Model\_Number\_JSM-F100 Field Emission

**Record Creation Time:** 20220129T080349+0000

**Record Last Update:** 20260815T182633+0000

### Ratings and Alerts

No rating or validation information has been found for JEOL: JSM-F100 Field Emission Scanning Electron Microscope (SEM).

No alerts have been found for JEOL: JSM-F100 Field Emission Scanning Electron Microscope (SEM).

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## Data and Source Information

**Source:** [SciCrunch Registry](#)

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## Usage and Citation Metrics

We have not found any literature mentions for this resource.